## Search Notes



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Reexamination TANAKA ET AL.

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Examiner

**Art Unit** 

Leung, Quyen P

2874

## **SEARCHED**

Class	Subclass	Date	Examiner
385	14, 15, 31-32, 39, 47, 50, 129-132	10/24/07	QPL

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Search Notes	Date	Examiner
US PTO EAST DATABASE SEARCHED		

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	US PGPUBS TEXT SEARCHED	10/24/07	QPL

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